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### Ultra-broadband and highly responsive photodetectors based on a novel EuBiTe<sub>3</sub> flake material at room temperature<sup>†</sup>

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We report a broadband photodetector based on the novel material EuBiTe<sub>3</sub>. The devices are operated at room temperature in the wavelength range from ultraviolet (370 nm) to near-infrared (1550 nm) with good reproducibility. Our results showed photoconductive responsivities greater than 1 A W<sup>-1</sup> in the ultraviolet, visible and near-infrared region and the response time is recorded to be as fast as about 40 ms.

Currently, the detection of electromagnetic radiation is a key issue in research and technological development, and broadband photodetection is central to various technological applications including imaging, remote sensing, optical communications, analytical applications and military surveillance.1-5 On account of its unique gapless electronic structure, graphene has been theoretically predicted to be a promising candidate material for broadband photodetection.<sup>6-9</sup> However, pure-graphene photodetectors suffer seriously from low absorption ( $\sim 2.3\%$ ) and ultrafast recombination of carriers, which limits their photoresponsivity to just several mA W<sup>-1</sup>.<sup>10,11</sup> Different methods including hybridization of quantum dots, integration of a waveguide, and plasmonic and band engineering have been exploited for improving the device performance<sup>12–14</sup> But the fabrication processes are very complex, which limits their mass production and most practical applications. In addition, most commercial photodetectors that operate in the visible or near-IR (NIR) region are based on silicon. However, Si photodetectors can only detect photons up to about 1110 nm owning to their finite bandgap (1.12 eV). Thus, the demand for exploring new materials which are favorable for both broadband and high performance photodetection is becoming increasingly eminent.

Here, we report a broadband photodetector based on the quasi-two-dimensional chalcogenide of EuBiTe<sub>3</sub>, which was

recently developed.<sup>15</sup> The devices are operated at room temperature in the wavelength range from UV (370 nm) to NIR (1550 nm) with good reproducibility. Our results showed photoconductive responsivities greater than 1 A  $W^{-1}$  in the UV, visible light and NIR region and the response time is recorded to be as fast as about 40 ms. Furthermore, in the absence of encapsulation, our detector suffers no obvious degradation after long-time exposure to atmosphere. We demonstrate that EuBiTe<sub>3</sub> photodetectors are able to be stably operated at room temperature as highperformance broadband photodetectors.

The EuBiTe<sub>3</sub> samples were prepared using the flux method and the parameters of the growth process were described in detail elsewhere.<sup>15</sup> The average size of the bulk crystals was 3 mm  $\times$  3 mm  $\times$  0.5 mm. We fabricated our photodetectors directly on EuBiTe<sub>3</sub> flakes with a thickness of 50 µm, which were exfoliated from the bulk crystals by means of the scotch tape method. Then the Au electrodes of 1 mm in length were deposited on the EuBiTe<sub>3</sub> surface by the thermal evaporation method. Finally, the EuBiTe<sub>3</sub> flakes were processed into rectangles with a photosensitive area of 0.12 mm  $\times$  1 mm.

Illuminations with wavelengths of 370 nm, 635 nm, 1064 nm and 1550 nm were generated from semiconductor lasers. The electrical characteristics of the EuBiTe<sub>3</sub> photodetector were evaluated using a Keithley 4200-SCS semiconductor parameter analyzer. All the photocurrent characteristics were analyzed under ambient conditions at room temperature.

Energy-dispersive spectroscopy (EDS), and X-ray diffraction (XRD) were conducted to study the constituents, structure and crystal quality of the flux-grown EuBiTe<sub>3</sub> flakes. EDS analysis (ESI,† Fig. S1) suggests that the components of the flakes deviate from the ideal stoichiometric ratio, with a deficiency of Bi atoms. According to previous studies,<sup>15</sup> this is due to the partial occupancy character for Bi elements. The XRD patterns of the EuBiTe<sub>3</sub> flakes are shown in Fig. 1(a). The sharp diffraction patterns of the (00*k*) series characterized the cleaved flakes well in the *ab*-planes, indicating that our EuBiTe<sub>3</sub> crystal samples are of high crystal quality. The inset shows that the EuBiTe<sub>3</sub> crystallizes in the orthorhombic crystal system with layered



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**Fig. 1** The crystal structure and electronic characteristics of EuBiTe<sub>3</sub>. (a) X-Ray diffraction patterns of EuBiTe<sub>3</sub> flakes. The inset shows the crystal structure of EuBiTe<sub>3</sub>. (b) The typical current–voltage curves of the EuBiTe<sub>3</sub> detector. The inset shows a schematic diagram of the EuBiTe<sub>3</sub> photodetectors.

Eu–Te–Bi slabs and Te monolayer stacking along the *c*-axis direction. A schematic diagram of a typical EuBiTe<sub>3</sub> photodetector is depicted in the inset of Fig. 1(b). The device consists of a EuBiTe<sub>3</sub> flake and two Au electrodes. The Au electrodes were deposited on the EuBiTe<sub>3</sub> surface by the thermal evaporation method. Fig. 1(b) shows the typical current–voltage (*I–V*) curves of our devices at room temperature (RT). Ohmic contact between the electrodes and the EuBiTe<sub>3</sub> flake is observed from Fig. 1(b), which can ensure that the intrinsic photoresponse from the EuBiTe<sub>3</sub> flakes is acquired instead of the effect of a hetero-junction between the flakes and the Au electrodes. Besides, as the current under illumination is symmetric, the possible photovoltaic effect in the devices can be excluded<sup>16,17</sup> Therefore, the architecture of our detectors is proposed to be of photoconductive type.

Fig. 2 summarizes the photoresponse of the  $EuBiTe_3$  photodetector for NIR(1550 nm) for instance. The switching behavior is clearly observed in Fig. 2(a). The device generates significant photocurrent under periodic illuminations. We can see that the photocurrent ramps to a high level under illumination and annihilates after removing the illumination. Fig. 2(b) shows the decay time of the photodetector and the saturation time is shown in the inset of Fig. 2(b). For decay time analysis, the twocomponent decay function was used:

$$I_t = I_1 e^{-t/\tau_1} + I_2 e^{-t/\tau_2}$$

where  $I_t$  is the normalized decaying photocurrent, and t is the time after switching off the illumination. Two different decay components were found, with the fast one being below 40 ms and the slow one being at a magnitude of around ~1 s. The intensity of the slow one  $I_2$  contributed a small part (13%) to the decay process for our measurements. On the one hand, we ascribed the  $I_2$  component to the background bolometric effect due to the heat exchange between the device and the surroundings during experiments (considering the bad-heat conductance between the devices and their surroundings, *i.e.* atmosphere or glass-substrates, the decay time of the bolometric effect will



Fig. 2 The performances of the EuBiTe<sub>3</sub> photodetector. (a) Time-dependent switching behavior of the photocurrent. Device area:  $1 \text{ mm} \times 0.12 \text{ mm}$ , power density: 490 mW cm<sup>-2</sup>. (b) The photoresponse decay process of our detectors (bottom panel) under lasers at wavelengths of 1550 nm. Two decay components were found at each case, with the fast one ( $\tau_1$ ) about 40 ms and the slow one ( $\tau_2$ ) around the order of ~1 s. (c) Voltage-dependent photocurrent at various light intensities. (d) Power-dependent photocurrent. Source-drain voltage: 1 V. (e) Stability of the EuBiTe<sub>3</sub> photodetector; red is stored in ambient environment for 3 months without any encapsulation. The curve is horizontally shifted for clarity.



Fig. 3 Ultra-broadband photoresponse of the EuBiTe<sub>3</sub> photodetector. Time-dependent switching behavior under illumination of (a) 370 nm, power density: 70 mW cm<sup>-2</sup>, (b) 635 nm, power density: 260 mW cm<sup>-2</sup> and (c) 1064 nm, power density: 1.7 W cm<sup>-2</sup>.

be more sensitive to the surroundings); on the other hand, the  $I_2$  component could also be caused by the photogating effect.<sup>18</sup> Thus, we consider the fast one as intrinsic and estimate the response time of photo-generated carriers to be about 40 ms. Besides, the time dependence shows weak light intensity dependence (see ESI,† Fig. S2).

Fig. 2(c) and (d) show the voltage-dependent photocurrent and power-dependent photocurrent, respectively. Obviously, we can see that the photocurrent is linearly proportional to both the driving voltage and the incident power. For the driving voltage, a large external voltage can efficiently restrain the recombination of photogenerated carriers, so that carrier separation is easier. Therefore, the photocurrent increases as the voltage increases. For the incident power, a larger number of electron-hole pairs are generated under stronger illumination. The good linear relationship between photocurrent and power suggests that our device can effectively distinguish different light intensities. In general, our device can have good tunability for multi-purpose applications because of the linear dependence on both the voltage and the incident power.<sup>19–21</sup>

In addition, the stability is a crucial factor for the photodetector in practical applications. For example, some photodetectors based on organic materials<sup>22,23</sup> are not stable because of their weak oxidation resistance. Thus, the durability to oxidative degradation in an ambient environment is investigated. Fig. 2(e) shows the performance of our device before and after storage for 3 months in an ambient environment without any encapsulation; there is no obvious reduction observed between the before and after. Therefore, owing to the low chemical activity of the compound, the EuBiTe<sub>3</sub> photodetector exhibits excellent stability in an ambient environment.

The spectral response range is another important performance parameter of the photodetector. For a photoconductive detector (usually referred to as a semiconductor detector), the spectral response range is closely related to the bandwidth of the detector. On account of the narrow-gap (0.3 eV),<sup>15</sup> EuBiTe<sub>3</sub> is predicted to be a promising candidate material for broadband photodetection. Fig. 3 shows the broadband photoresponse of the EuBiTe<sub>3</sub> photodetector. As observed, Fig. 3(a)–(c) and Fig. 2(a) show good switching behavior under periodic illumination with different laser wavelengths (370 nm, 635 nm, 1064 nm, and 1550 nm), suggesting an ultra-broadband photoresponse range from ultraviolet to infrared for our devices. For a photoconductive detector, the signal component of sensitivity is quantified by the current photoresponsivity (*R*), which is the ratio of photocurrent ( $I_{ph}$ ) to the incident light power ( $P_{in}$ ) and expressed as  $R = I_{ph}/P_{in}$ , in the units of A W<sup>-1</sup>. Fig. 4(a) shows the spectral responsivity curve. The responsivity at 370 nm, 635 nm, 1064 nm and 1550 nm is 2.8 A W<sup>-1</sup>, 1.9 A W<sup>-1</sup>, 1 A W<sup>-1</sup> and 1.7 A W<sup>-1</sup>, respectively. The responsivity reaches the maximum value at 370 nm and the minimum value at 1064 nm. Interestingly, the responsivity shows weak light intensity dependence in our device (see ESI,† Table S1). From the optical absorbance spectrum of EuBiTe<sub>3</sub> crystals (Fig. 4(a)), the responsivities of different wavelengths are well consistent with the intrinsic absorption of the EuBiTe<sub>3</sub>. Evidently, our devices demonstrated high responsivity in the UV, VIS and NIR range measured with magnitudes greater than 1 A W<sup>-1</sup>, as



**Fig. 4** Optical absorbance and responsivity characteristics for EuSbTe<sub>3</sub> detectors. (a) RT *ab*-plane optical absorbance spectrum of EuBiTe<sub>3</sub> crystals. (b) The responsivity for our EuBiTe<sub>3</sub> detectors under illumination with wavelengths from UV to NIR based on the same device. Device area: 1 mm  $\times$  0.12 mm.

required by most applications. Such broad responsivity range is attributed to the narrow band gap of the EuBiTe<sub>3</sub>, as the photons from UV to NIR have enough energy to excite the electrons from the conduction band to the valence band. Our observations of the responsivities in EuBiTe<sub>3</sub> detectors far surpass the initially reported devices based on other 2D materials, such as 1 mA W<sup>-1</sup> for pure graphene,<sup>1</sup> and 7 mA W<sup>-1</sup> for MoS<sub>2</sub>.<sup>24</sup> Most remarkably, compared with the traditional silicon detector, the EuBiTe<sub>3</sub> photodetector exhibited high responsivity to ultraviolet and telecommunication wavebands ( $\lambda = 370$  nm, and 1550 nm) at RT. However, the extremely high dark current at the magnitude of 10<sup>-3</sup> A lead to a detectivity of 0.6 × 10<sup>-9</sup> cm Hz<sup>1/2</sup> W<sup>-1</sup> (see ESI,† S3).

In summary, we have fabricated a photodetector based on flux-grown EuBiTe3 flakes and investigated its photoresponse. We demonstrate devices with stable ultra-broadband photoresponse from 370 nm to 1550 nm with good reproducibility at room temperature. Our devices exhibited high responsivity in the range from UV to NIR with magnitudes greater than 1 A  $W^{-1}$ . In particular, the EuBiTe<sub>3</sub> photodetector exhibited high responsivity to ultraviolet and telecommunication wavebands ( $\lambda = 370$  nm, and 1550 nm) at RT along with a fast decay time of  $\sim$  40 ms. In addition, our devices show that the photocurrent is linearly proportional to the driving voltage and the incident power, offing good tunability for multi-purpose applications. Furthermore, our devices without any encapsulation suffer no obvious degradation after a long time period of three months of exposure to air. In general, we demonstrate that EuBiTe3-based photodetectors are able to be stably operated at room temperature as high-performance broadband photodetectors.

## Conflicts of interest

There are no conflicts to declare.

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